Search Notes



Application/Control No.	Applicant(s)/Patent Under Reexamination
10585691	FUKUSHIMA ET AL.
Examiner	Art Unit
HEE-YONG KIM	2621

SEARCHED						
Class	Subclass	Date	Examiner			
348	42-60	4/20/2010	H.K			

SEARCH NOTES				
Search Notes	Date	Examiner		
Inventor Search at Edan	4/18/2010	H.K		
parallax and lenticul\$3 and longitudinal	4/20/2010	H.K		
parallax and lenticul\$3 and 45 degree	4/20	H.K		
348/42-60.ccls. and (view\$2 (specific or position or eye))	4/20	H.K		
48/42-60.ccls. and (view\$2 (specific or position or eye)) and lentic\$4 and (shift same parallax)	4/20	H.K		
parallax and toshiba.as.	4/20	H.K		
parallax and lentic\$4 and (adjust\$3 with view\$3)	4/22	H.K		
parallax and lentic\$4 and (shift with view\$3)	4/22	H.K		
(pin-hole or pinhole) camear and (focal length and distance)	4/23	H.K		
Discussed with Dave C at QEM and suggest string (lenticular and (shift same parallax)	4/20	H.Kand D.C		
Discussed with Andy Rao and he suggesed class 348/42-60, searched to get one reference (6,329,963) but it is not relevant.	4/20, 4/21	H.K and A.R		

INTERFERENCE SEARCH				
Class	Subclass	Date	Examiner	

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